

Figure 14.15 Time-progressive X-ray diffraction line profiles for the (511)/(333) reflection for PVD CdTe/CdS thin-film structures deposited at 250°C and treated in CdCl₂:Ar:O₂ vapor at 420°C. Positions of pure CdTe and CdTe_{1-x}S_x alloy with $x = 0.06$ are indicated

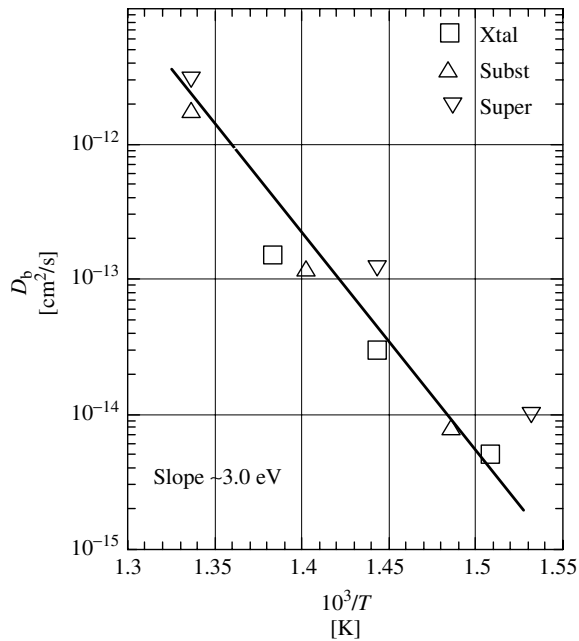


Figure 14.16 Arrhenius plot of bulk-diffusion coefficients versus inverse of treatment temperature for values obtained by modeling XRD line profiles of thin-film CdTe/CdS samples and from AES depth profiling of S distribution in CdTe single crystal [73]